First Order Reversal Curve (FORC)测量和其后续分析为常规磁滞回线提供了额外的见解，以深入了解磁性材料的磁性反转机制，包括磁性材料的磁性材料、薄膜和纳米图案化样本。这些曲线家族可以提供一种定性/定量的磁性反转机制指纹，以及区分可逆和不可逆的磁性反转机制。进一步的应用包括能够计算磁性反转机制的相分数以及磁化率和相互作用场分布。

**Key Features:**
- 完全自动化的FORC acquisition using MultiVu
- FORC distributions can be calculated and displayed in real-time during a measurement
- Users can change between the \((H_c, H_u)\) and \((H, H_r)\) coordinate systems as well as update the smoothing factor, color scheme, and measurement units on the fly
- Compatible with any Quantum Design VSM configuration including the standard and large bore coil sets and the VSM oven
- Resulting output data file is preformatted for easy import into the FORCinel post-processing software

**MultiVu User Interface**

FORC measurements can be easily incorporated into standard VSM sequences. The FORC distribution of a high anisotropy FePt thin film is plotted in the \((H_c, H_u)\) coordinate system. Sample provided by Prof. Kai Liu, Georgetown University.

See VSM Standard / Large Bore / Oven Specifications for Details

**Operational Range**

1.8 to 1000 K; 0 to 16 T

Specifications are subject to change without notice.